

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination BEDELL ET AL.	
		Examiner A. Dexter Tugbang	Art Unit 3729	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,278,591	08-2001	Chang et al.	360/126 x
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	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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